

Claims

- [Claim 1] A test device for testing an electric characteristic of an object to be tested, the test device comprising:
 a block comprising a probe hole;
 a probe supported in the probe hole and retractably configured to connect a first contact point and a second contact point; and
 a coaxial cable comprising an insulated sheath, a main core surrounded with the insulated sheath, and a probe contact portion exposed from the insulated sheath and extended from the main core so as to be in contact with the probe, wherein
 an axis of the probe is spaced apart from an axis of the coaxial cable at an end of the coaxial cable which the probe contact portion extends from the main core, and
 the probe contact portion is extended from the main core toward the axis of the probe,
wherein the probe contact portion is bent one or more times.
- ~~[Claim 2] A test device for testing an electric characteristic of an object to be tested, the test device comprising:
 a block comprising a probe hole;
 a plurality of probes supported in the probe hole and retractably configured to connect a first contact point and a second contact point;
 a coaxial cable comprising an insulated sheath, a main core surrounded with the insulated sheath, and a probe contact portion exposed from the insulated sheath and extended from the main core toward the probe so as to be in contact with the probe; and
 a core reinforcer sheathed on the probe contact portion.~~
- [Claim 3] The test device according to claim 1, further comprising a core reinforcer sheathed on the probe contact portion.
- [Claim 4] The test device according to claim 2 or 3, wherein the core

reinforcer is formed by applying and hardening liquid resin.

[Claim ~~54~~]

The test device according to claim 2-~~or 3~~, wherein the core reinforcer comprises a conductive material.

[Claim ~~65~~]

The test device according to claim 2-~~or 3~~, wherein the core reinforcer comprises an insulating material, and is partially removed from the probe contact portion to be in contact with the probe.

[Claim ~~76~~]

The test device according to claim 2-~~or 3~~, further comprising a cable supporter which comprises a cable accommodating hole to accommodate the coaxial cable, and a cable supporting block coupled to the ~~conductive~~ block while aligning the probe hole with the cable accommodating hole.

[Claim ~~87~~]

The test device according to claim 2-~~or 3~~, wherein the probe contact portion comprises a flat portion of which a portion to be in contact with the probe is grinded flat.

[Claim ~~98~~]

The test device according to claim ~~87~~, wherein the flat portion comprises a plating layer plated with a conductive material.

[Claim ~~109~~]

The test device according to claim 2-~~or 3~~, wherein the probe contact portion comprises a plating layer of which a portion to be in contact with the probe is plated with a conductive material.

[Claim ~~110~~]

The test device according to claim ~~98~~, wherein the plating layer is plated more largely than an area of the flat portion.

[Claim ~~111~~]

The test device according to claim ~~109~~, wherein the plating layer is plated more largely than a cross-sectional area of the main core.

~~[Claim 13]~~

~~The test device according to claim 1, wherein the probe contact portion is bent one or more times.~~

[Claim ~~12~~]

The test device according to claim 1, wherein the probe contact portion comprises
a linear extension portion extended along ~~an~~ the axis of the coaxial cable; and
a contact portion extended from the linear extension portion toward ~~an~~ the axis of the probe.

- | [Claim ~~15~~13] The test device according to claim ~~14~~12, wherein the contact portion is coupled to the linear extension portion.
- | [Claim ~~16~~14] The test device according to claim 2, wherein the core reinforcer comprises a conductive tube configured to accommodate the probe contact portion.
- | [Claim ~~17~~15] The test device according to claim ~~16~~14, wherein the core reinforcer comprises a conductive contact head provided at one end of the tube so as to be in contact with the probe.